

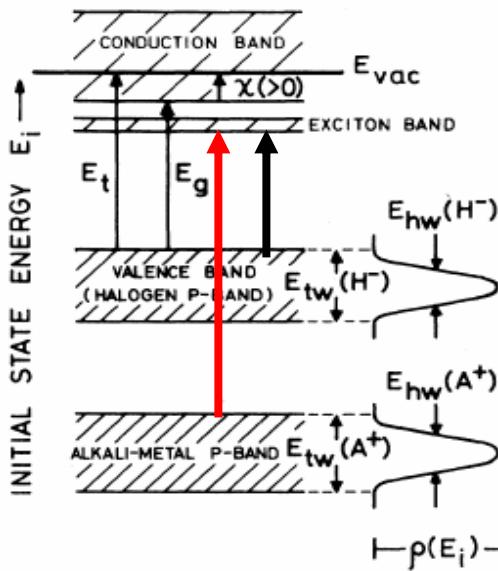
# Swift heavy ion induced damage in LiF: in ( $z < R$ ) and beyond ( $z > R$ ) the track

K. Schwartz, MF  
NoRHdia, June 2008

- Why LiF?
- Track morphology in LiF crystals:  
dependence on  $dE/dx$ ,  $E_{ion}$ ,  $\Phi$ ,  $T_{irr}$
- Color centers beyond the track ( $z > R$ ):
  - 1) radiation sources; 2) distribution of color centers; 3) peculiarities for various ions

Open questions and outlook





$\text{Li}^+ 2s$

$\text{F}^- 2p^6$

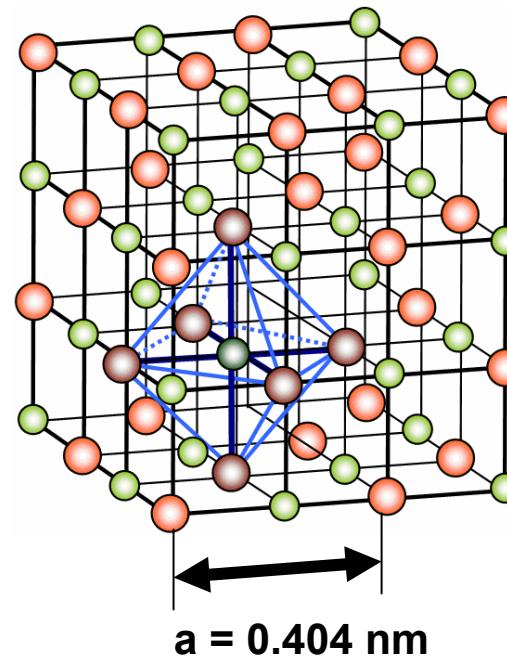
$\text{Li}^+ 1s^2$

**LiF, cubic**

$$E_g = 14.6 \text{ eV}$$

$$E_{\text{anion}} = 13.6 \text{ eV}$$

$$E_{\text{cat}} = 62 \text{ eV}$$



# Primary defect creation in dielectric materials

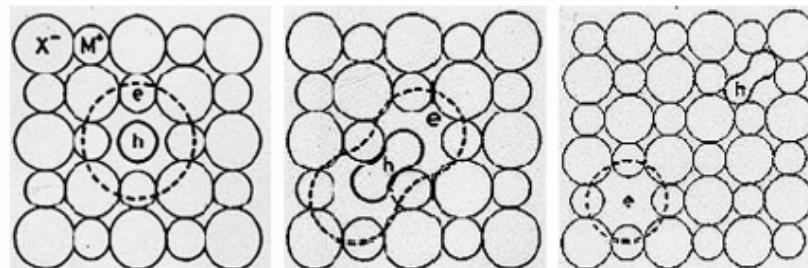
## 1. Atomic collisions

m m

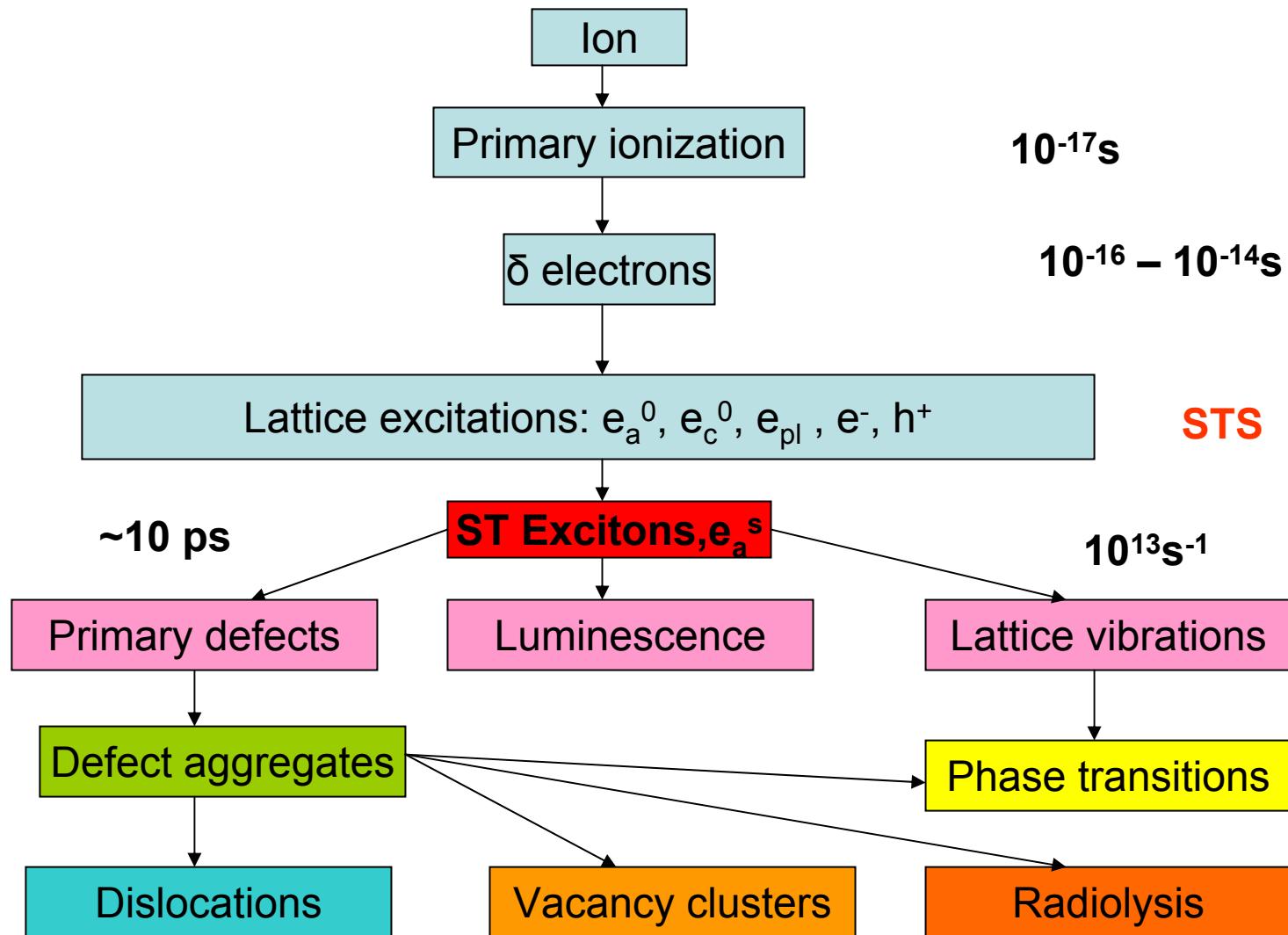
## 2. Decay of electronic excitations of the lattice

$$e^o \rightarrow e^s$$

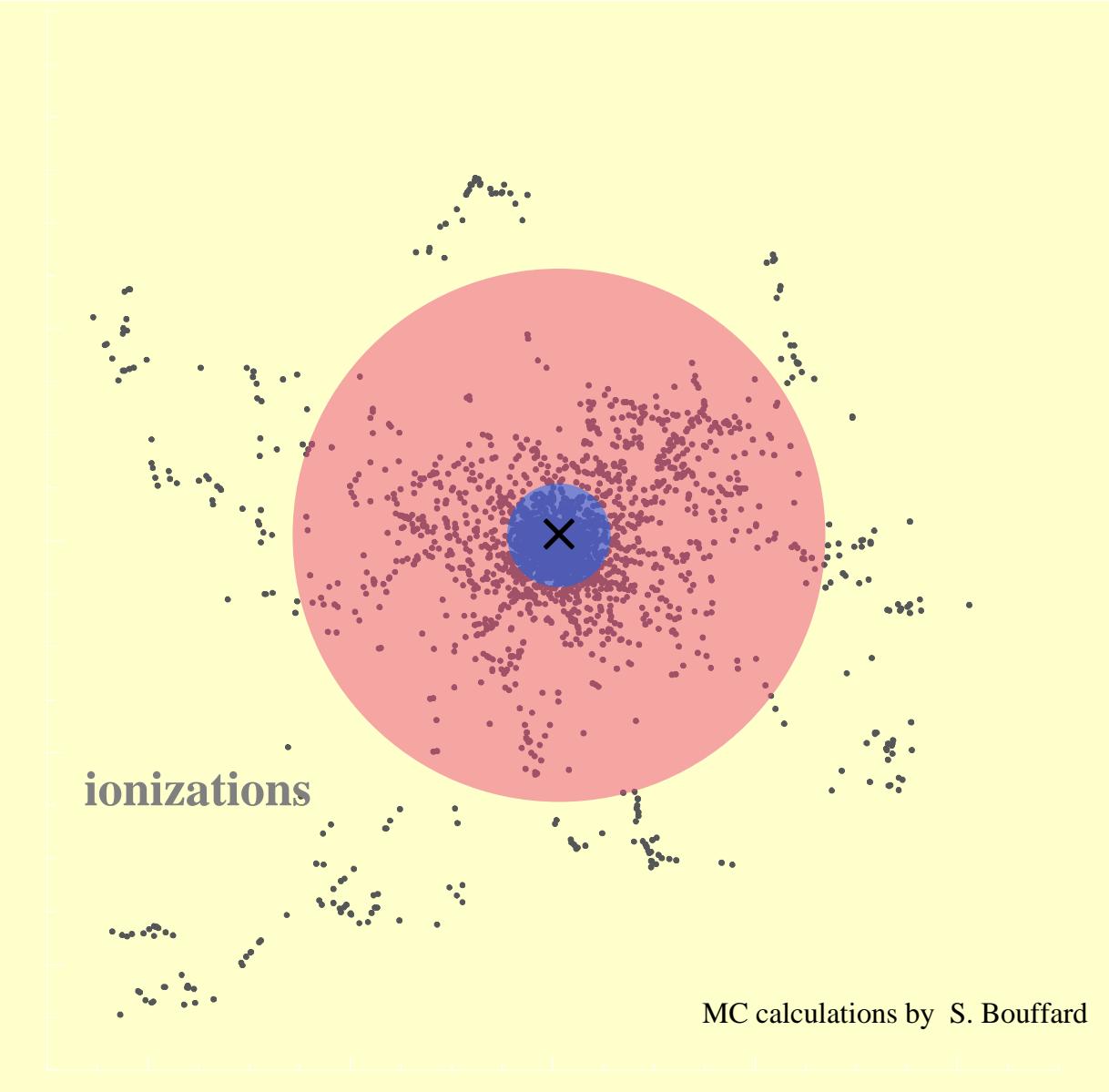
$$E_{ex}^s > E_{def}$$



# Energy conversion and defect creation in ionic crystals by the exciton mechanism



# Scheme of track morphology



**core**

**radius**    **1-2 nm**

**energy**     **$\sim 0.3 E_{\text{tot}}$**

**halo**

**radius**    **10-40 nm**

**energy**     **$\sim 0.7 E_{\text{tot}}$**

## Track morphology in alkali halides: Different damage via $dE/dx$

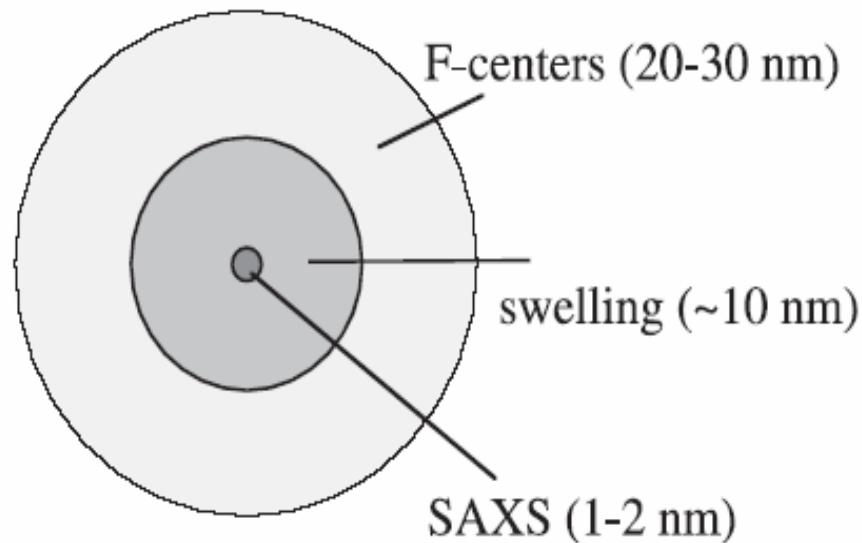
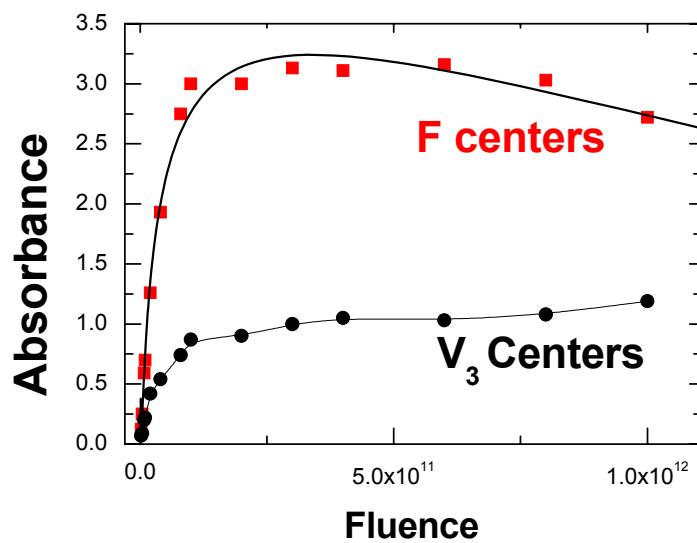


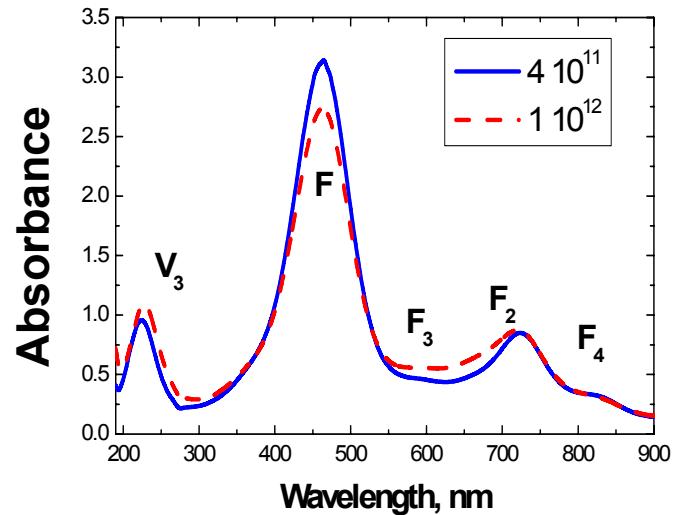
Fig. 14. The structure of tracks in LiF is described by (1) a large halo mainly consisting of single color centers, (2) a medium sized zone contributing to swelling, and (3) a small core region responsible for etching and SAXS.

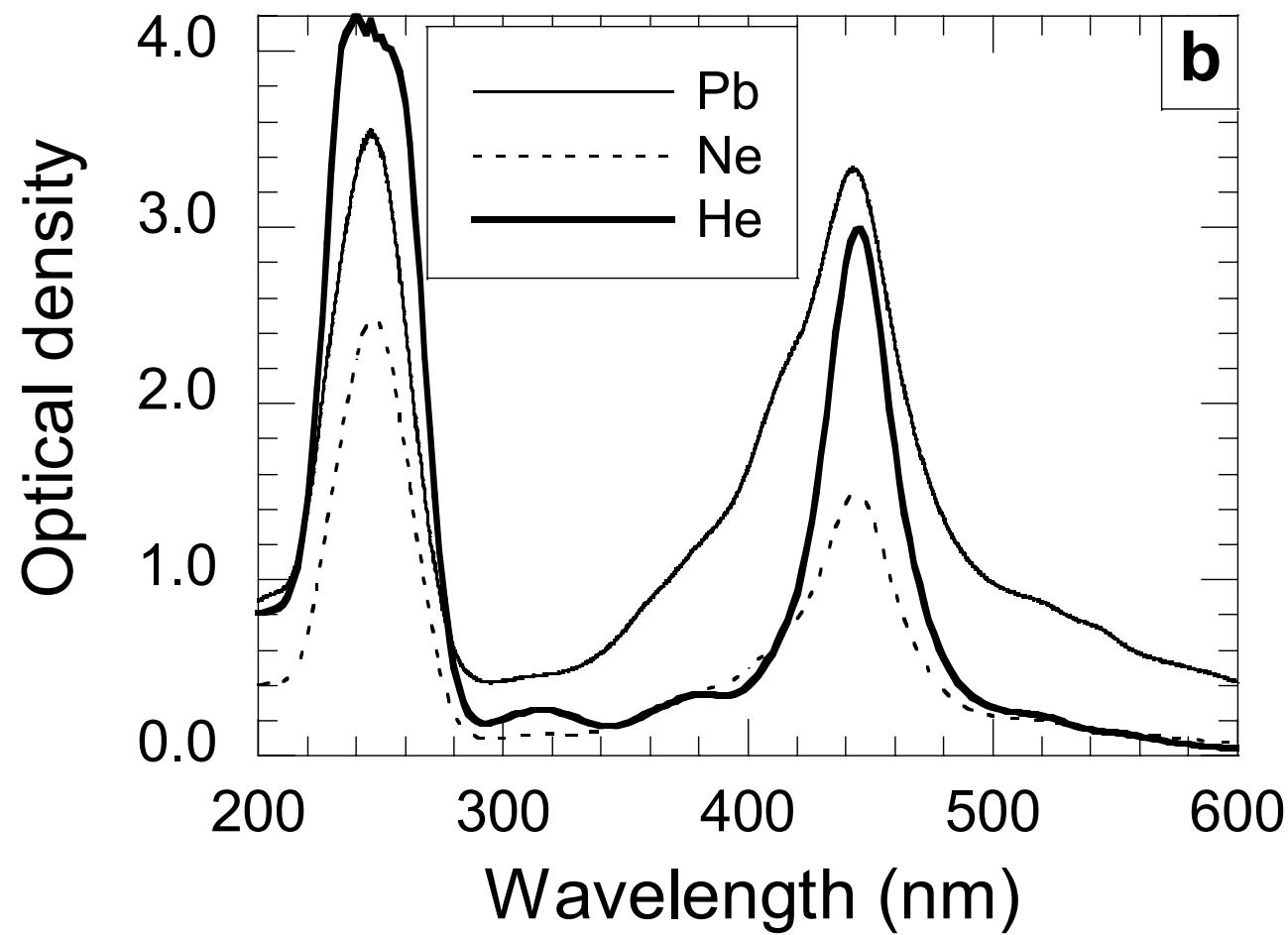
# Au 2187 MeV induced aggregation in NaCl at 300 K

$N_F$  decreases  $F \rightarrow F_n$



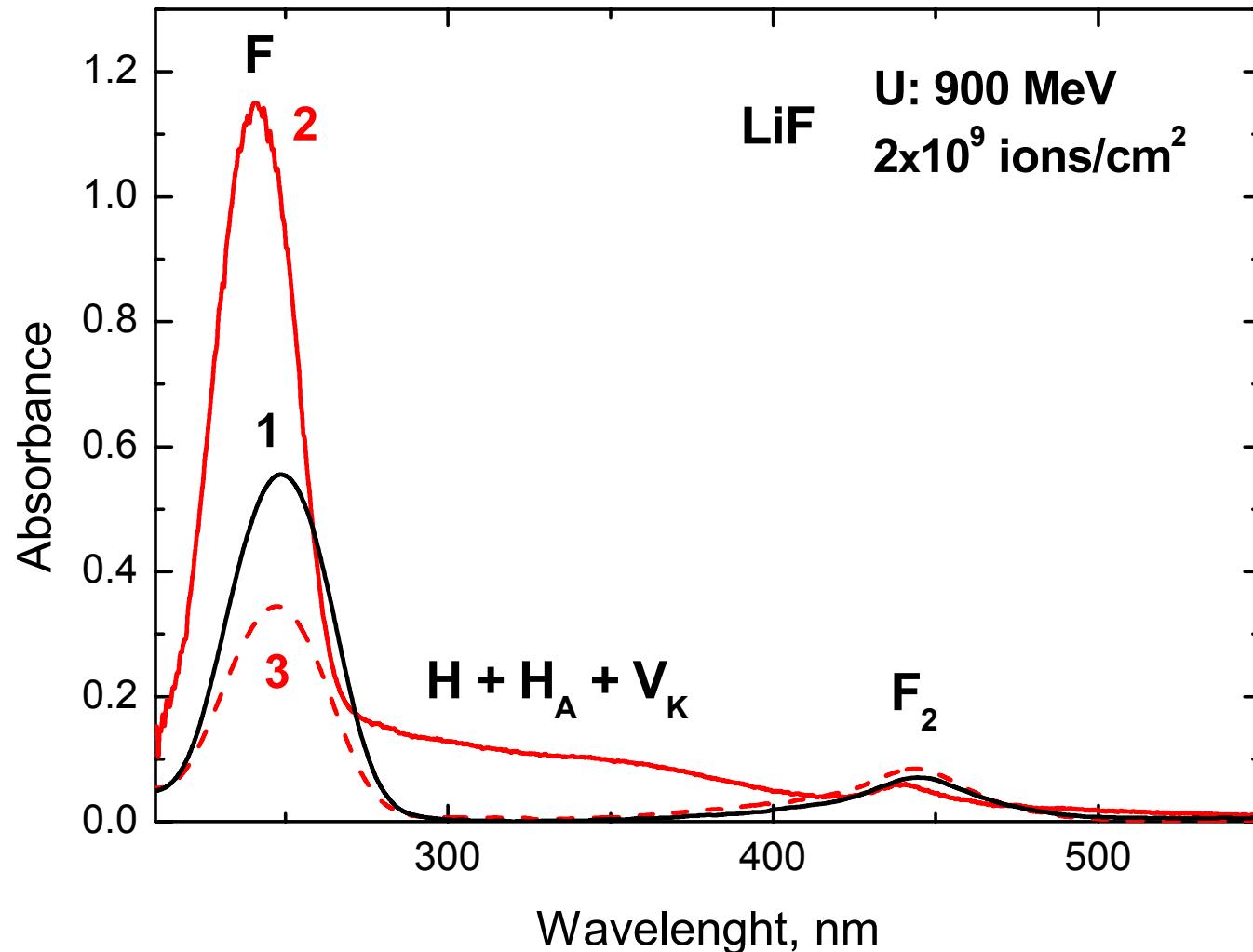
$N_{V3}$  further increase



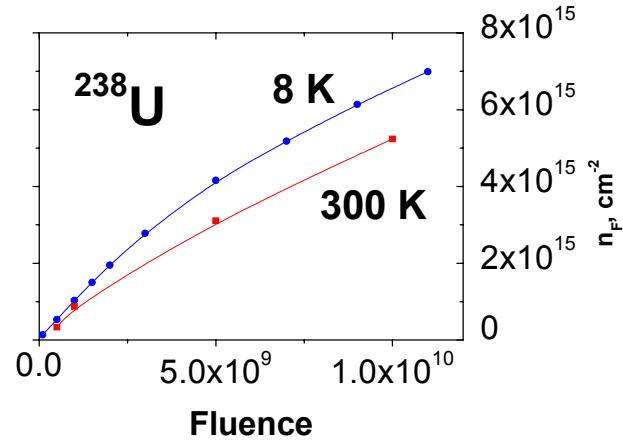
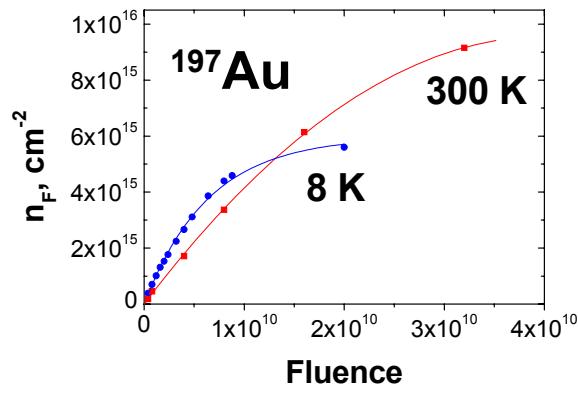
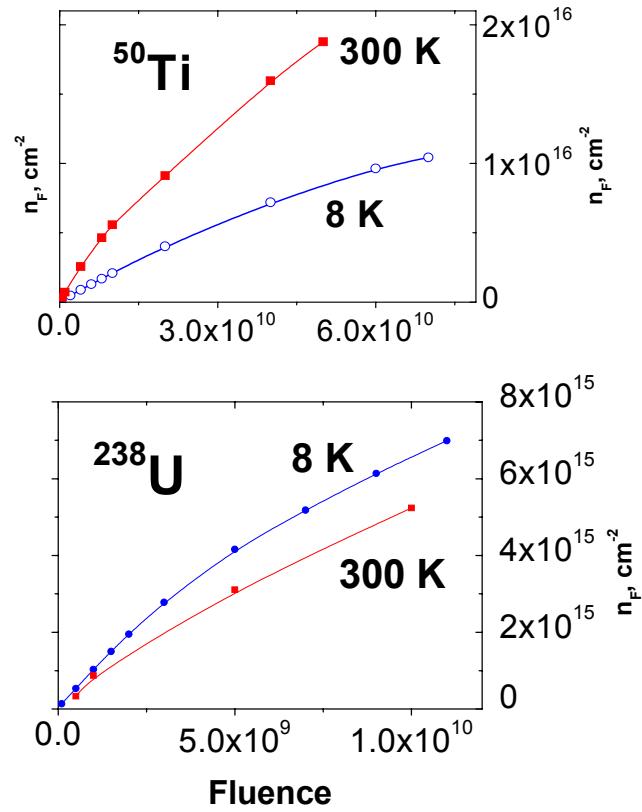
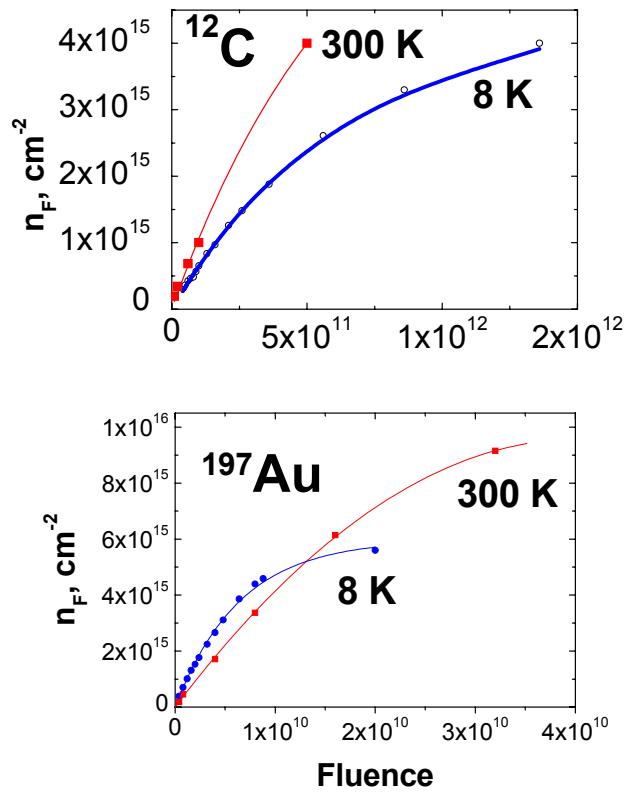


**He** 5 MeV,  $10^{14}$ ; **Ne** 31 Mev,  $10^{13}$ ; **Pb** 830 MeV,  $1.2 \times 10^{12}$

$1 - n_F(300 \text{ K}) = 5.5 \times 10^{15} \text{ cm}^{-2}$      $2 - n_F(8 \text{ K}) = 7 \times 10^{15} \text{ cm}^{-2}$   
 $3 - n_F(300 \text{ K}) = 3.3 \times 10^{15} \text{ cm}^{-2}$  after 8 K



# Efficiency of color center creation at 8 and 300 K

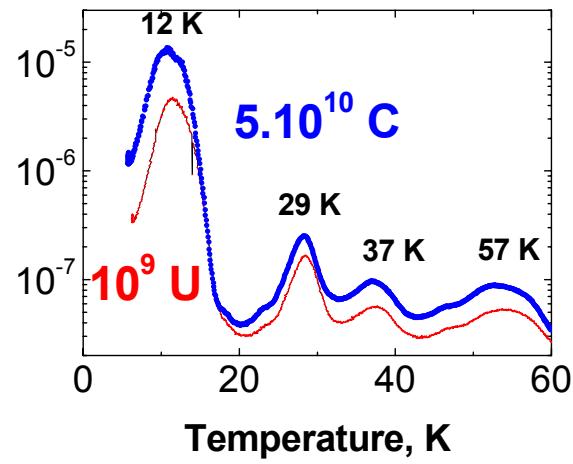


# TSL in LiF and NaCl Crystals at 8 K

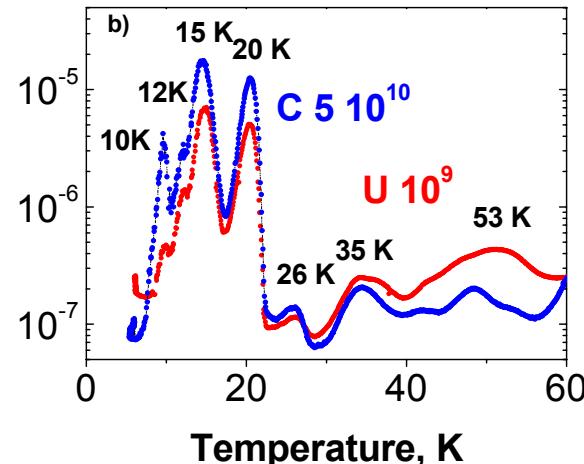
Defects with low thermal stability – low local heating in the track  
No dependence on  $dE/dx$

10 – 25 K I centers (Lushchik et al. [3]) 25 – 60 K H centers

**LiF**

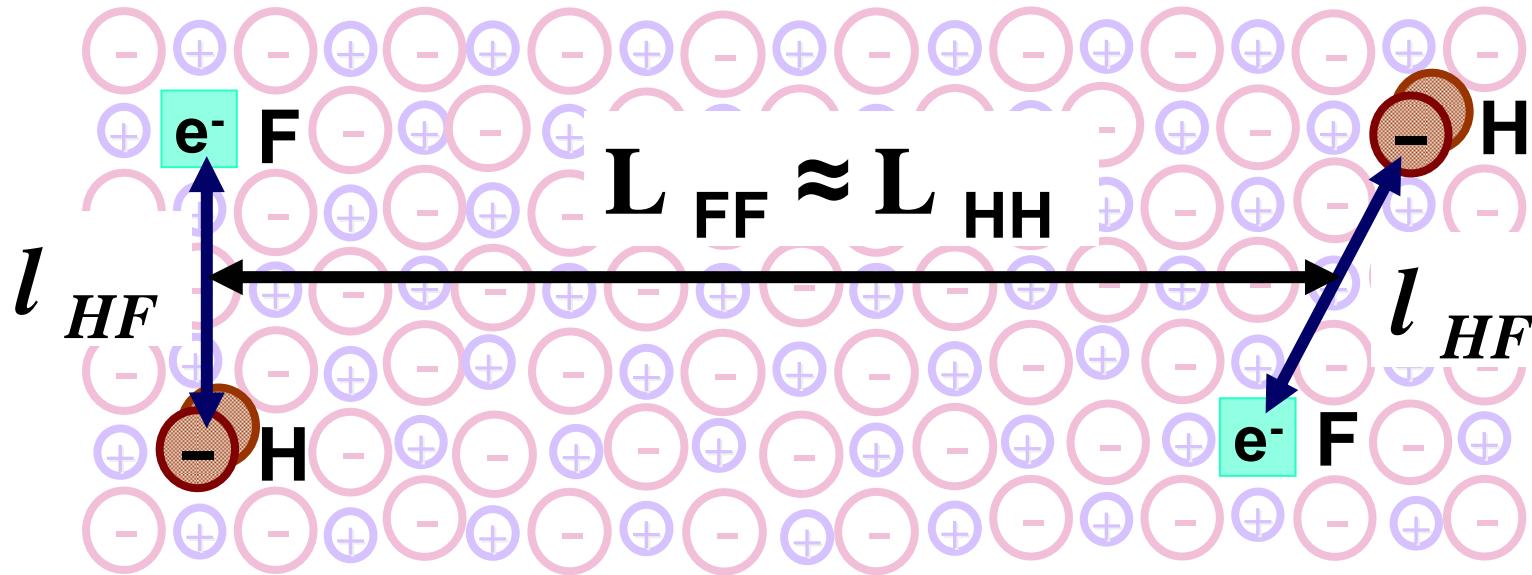


**NaCl**



# Defect separation lengths

Two lengths governing defect recombination and aggregation, *NIM B 245 (2006) 204*

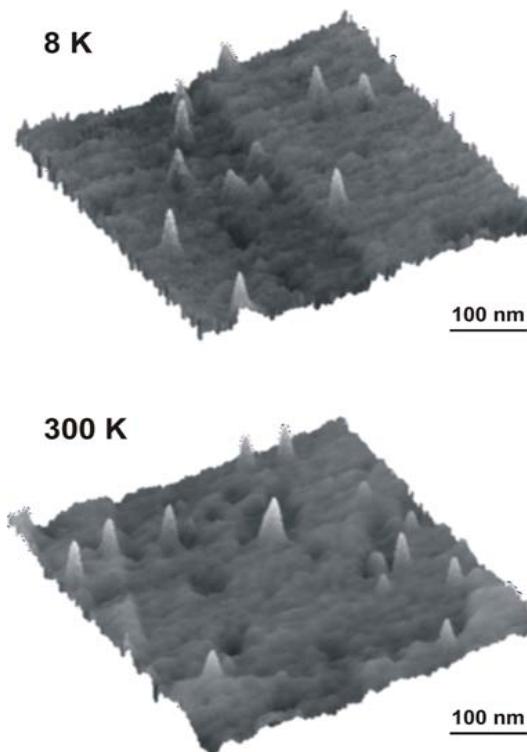


Separation of F and H centers in Frenkel pairs depends on local temperature during pair creation; Lushchik et al.(1992); Spaeth et al.(1994)

$$l \sim \sqrt{6D_H \tau} \geq l_{HF}^{\min} = 5a = 1.4 \text{ nm}$$

# Hillocks in LiF Irradiated with 1400 Pb ions at 8 K and 300 K

M. Lang et. al. Phys. Stat. Solidi (c) 4(2007) 1105



1. Determined by aggregates (track core damage)
2. Threshold  $dE/dx \sim 6 \text{ keV/nm}$
3. No dependence on  $T_{\text{irr}}$

**8 K**

$$d = 19.5 \pm 3 \text{ nm}$$

$$h = 0.9 \pm 0.2 \text{ nm}$$

**300 K**

$$d = 18.3 \pm 3 \text{ nm}$$

$$h = 0.8 \pm 0.2 \text{ nm}$$

**NaCl,**

*NIM B 225 (2005) 397*

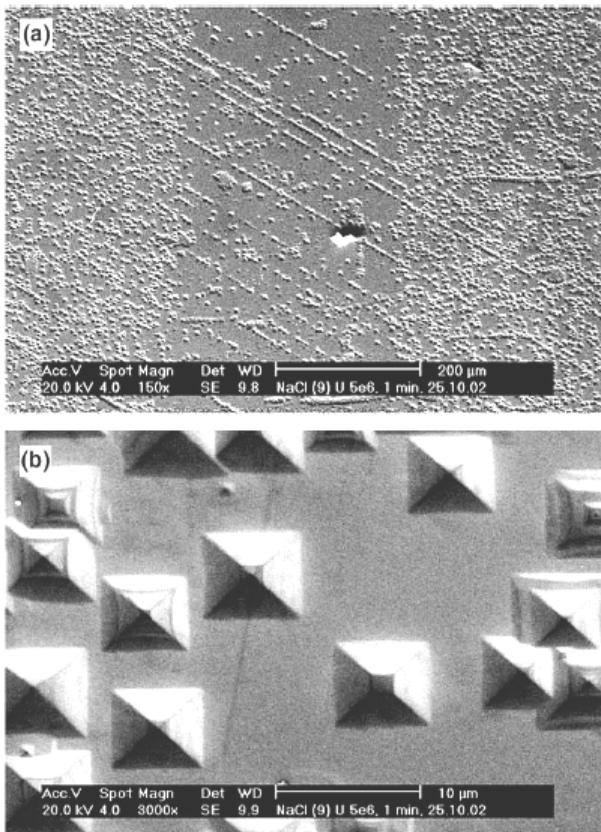


Fig. 4. SEM images at low (a) and high (b) magnification showing a NaCl surface irradiated through a structured mask with 11.1 MeV/u U ions ( $5 \times 10^6 \text{ cm}^{-2}$ ). After 1 min of room-temperature etching, masked (vertical central stripe) and irradiated areas can be recognized (a). Etch pits resulting from ion tracks (b) exhibit the same shallow pyramidal shape as etched dislocations in the masked area.

**LiF, Dislocation density**

*NIM B 209 (2003) 93*

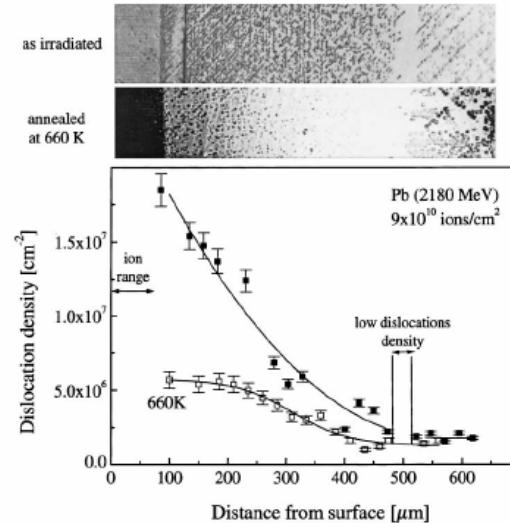
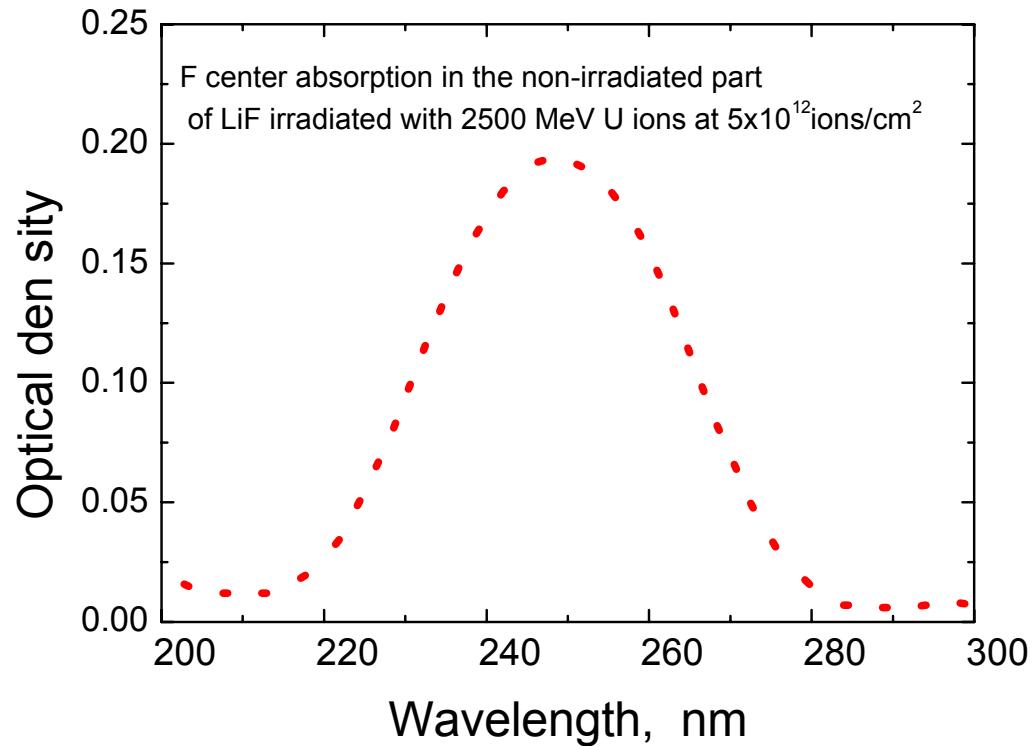
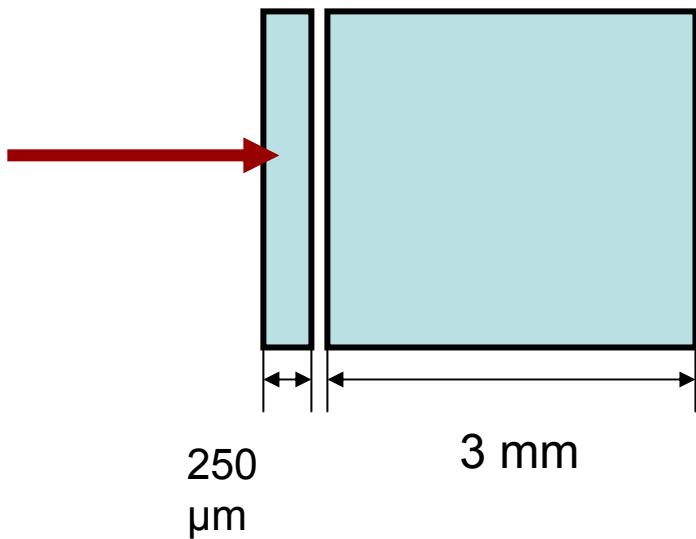


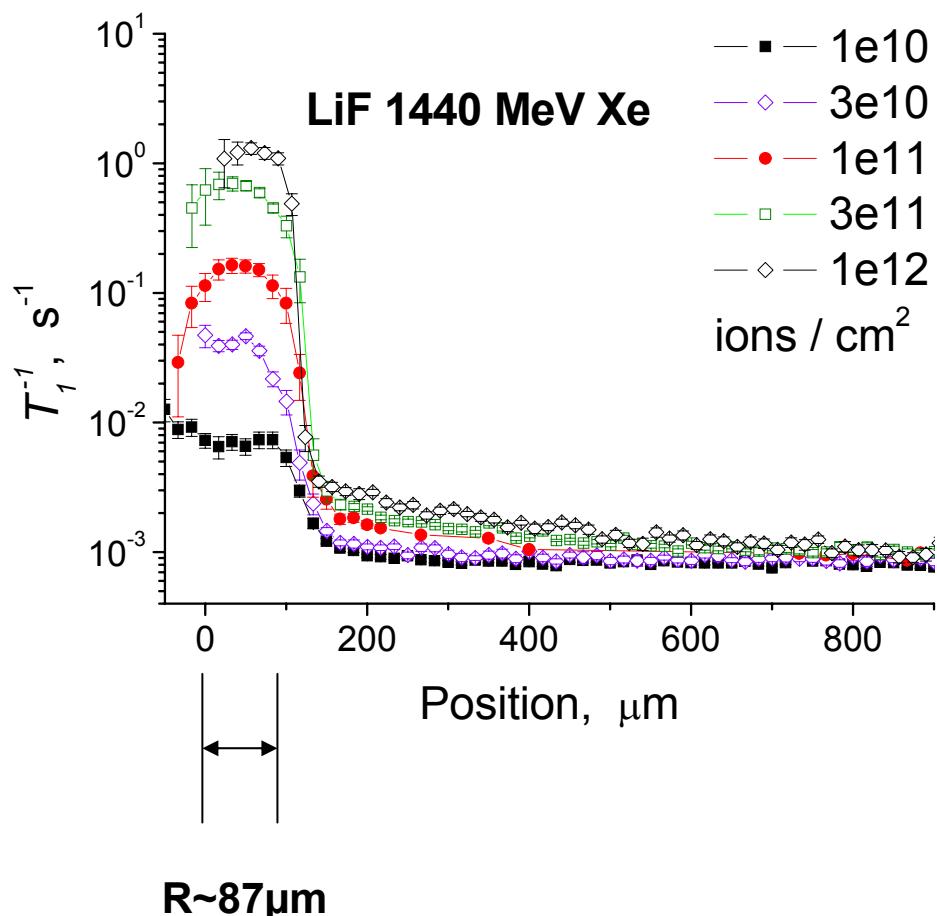
Fig. 9. Dislocations on etched cross-sections of crystals irradiated with 2180-MeV Pb ions before (top) and after (center) annealing at 660 K. The length scale of the micrographs correspond to the x-axis of the plot (bottom) with dislocation density as a function of sample depth.

**2500 MeV  $^{238}\text{U}$**

**LiF**



# Spatially resolved field gradient NMR, H. Stork et al.



$$T_1^{-1} \sim n_F$$

$$k = (\text{irradiated}) / (\text{non - irradiated})$$

$$k \sim 10^3$$

# F center concentration in the depth beyond the track: decreasing with the thickness

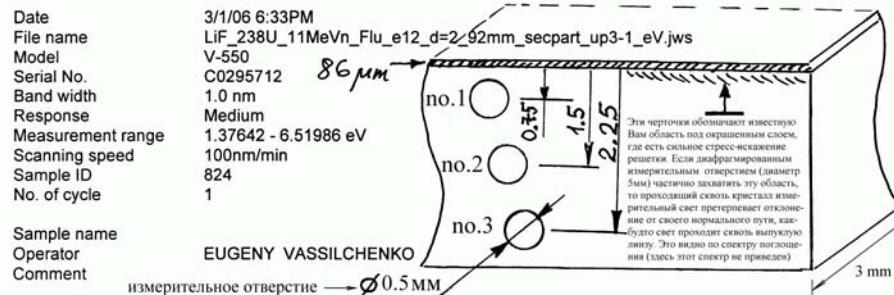
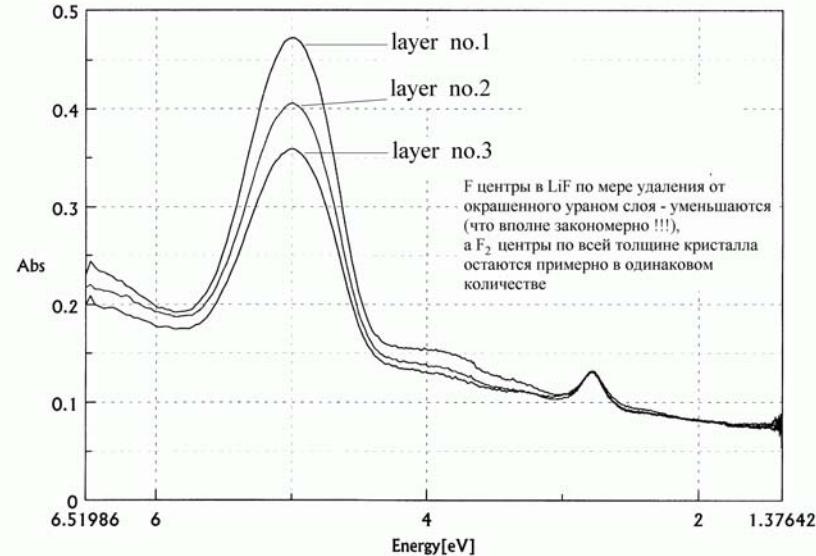
X-ray absorption

$$I = I_0 e^{-\mu d}$$

$$n_F(x) \sim \exp(-x/l)$$

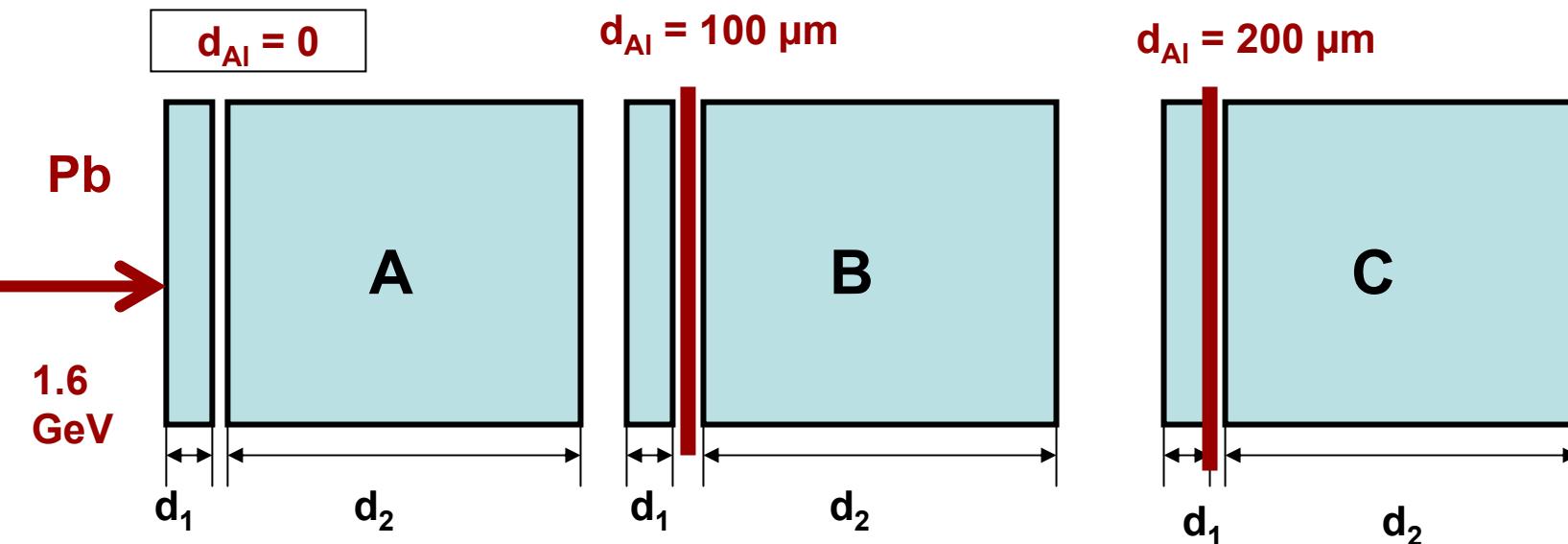
Exponential decrease of the X – ray intensity

$$n_F \sim I_x$$



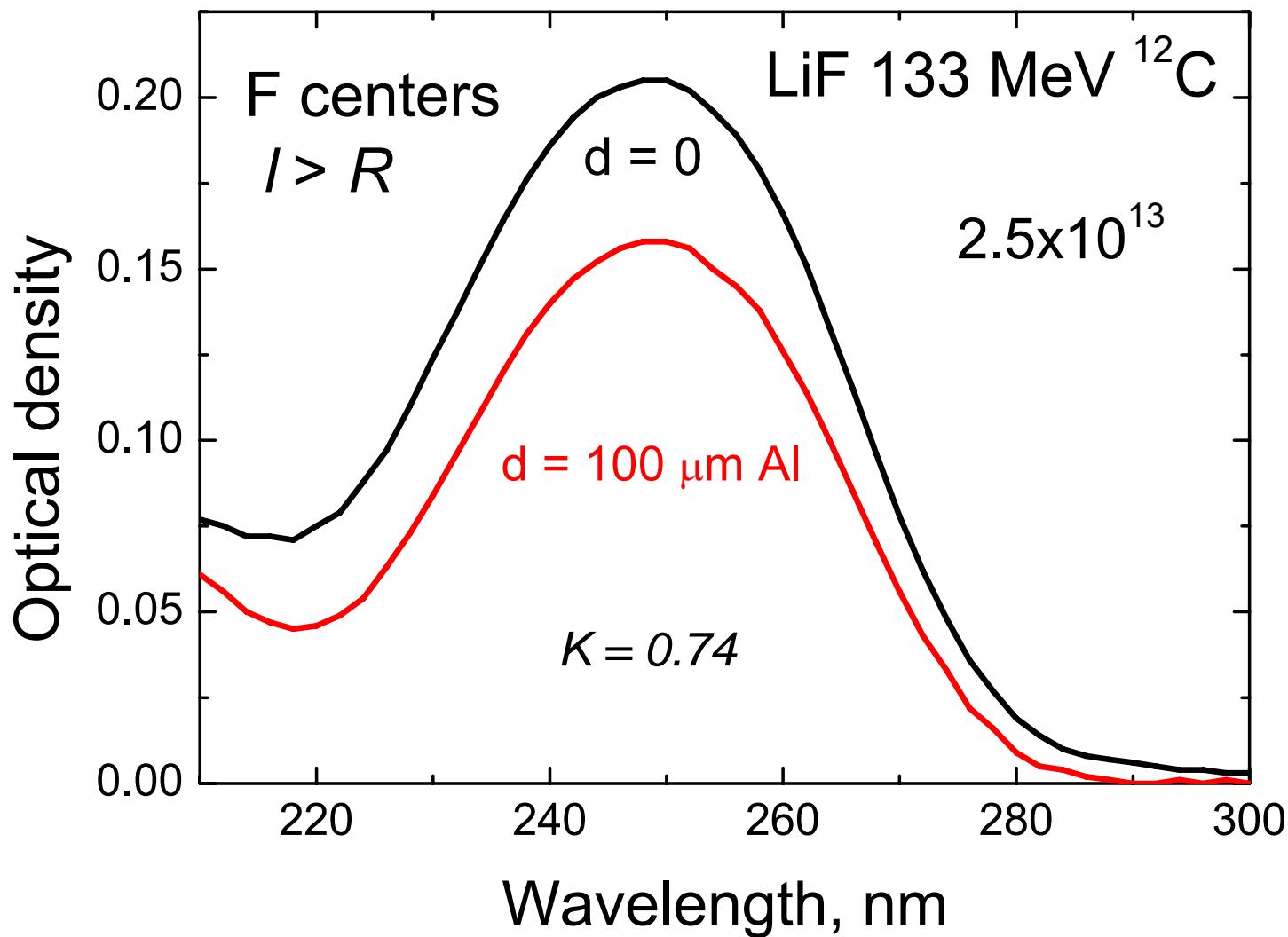
# Irradiation with 130 MeV $^{12}\text{C}$ ions through Al films

$$E_{\delta}^{\text{max}} \sim 16.7 \text{ keV}$$

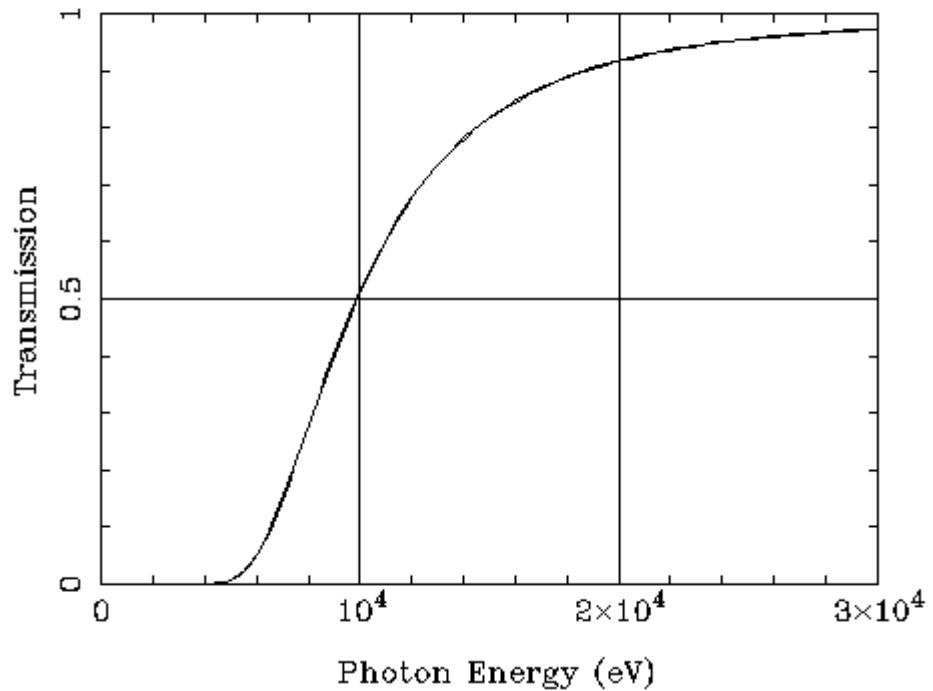


$$d_1 \approx 300 \mu\text{m}; d_2 \approx 3000 \mu\text{m} = 3 \text{ mm}$$

$$k_1 = D(\text{B}) / D(\text{A}) ; k_2 = D(\text{C}) / D(\text{A})$$



Al Density=2.6989 Thickness=100. microns



**Transmission  $k = 0.74$**

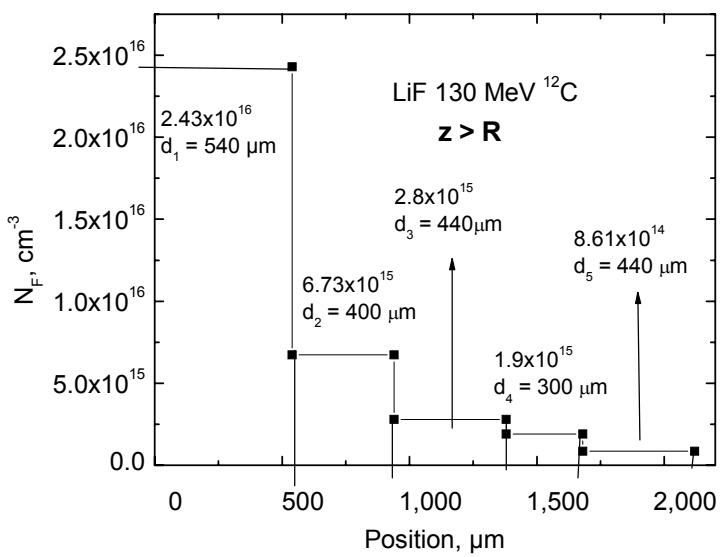
$E_x \approx 13 \text{ keV}$

**130 MeV  $^{12}\text{C}$**

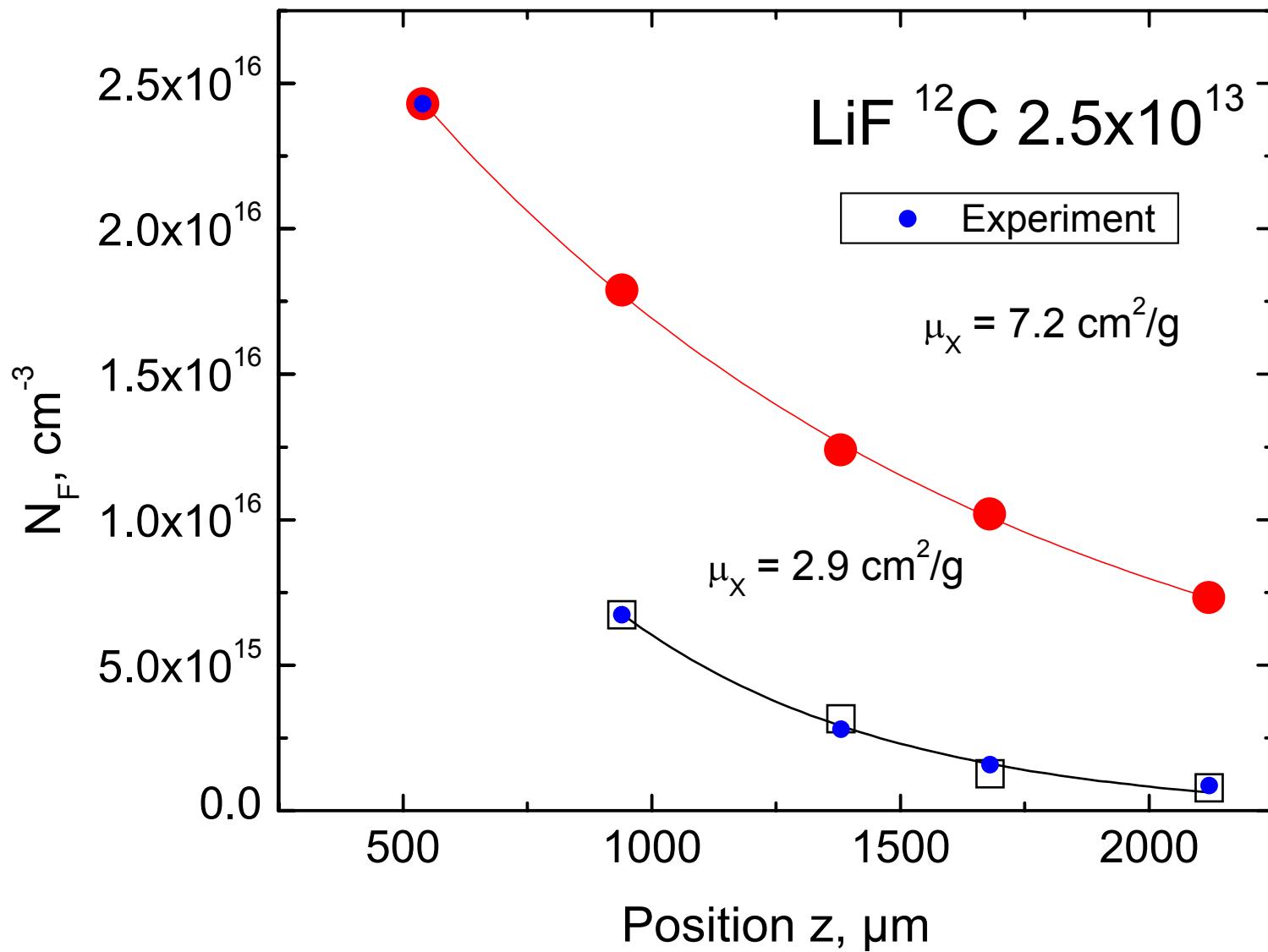


$$d_0 > R$$

$$d_{1-8} \text{ } 300 - 500 \mu\text{m}$$



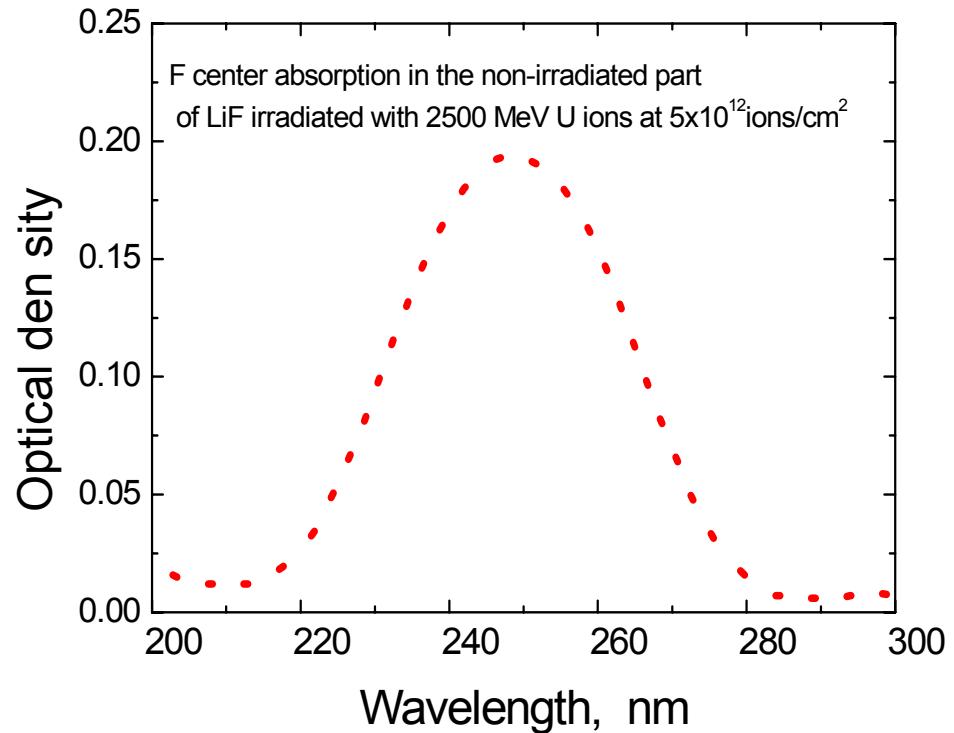
$$N_F(z_i) = N_F(z_{i-1}) \exp(-\mu_X \rho z)$$



## 2500 MeV U – ion induced F center absorption

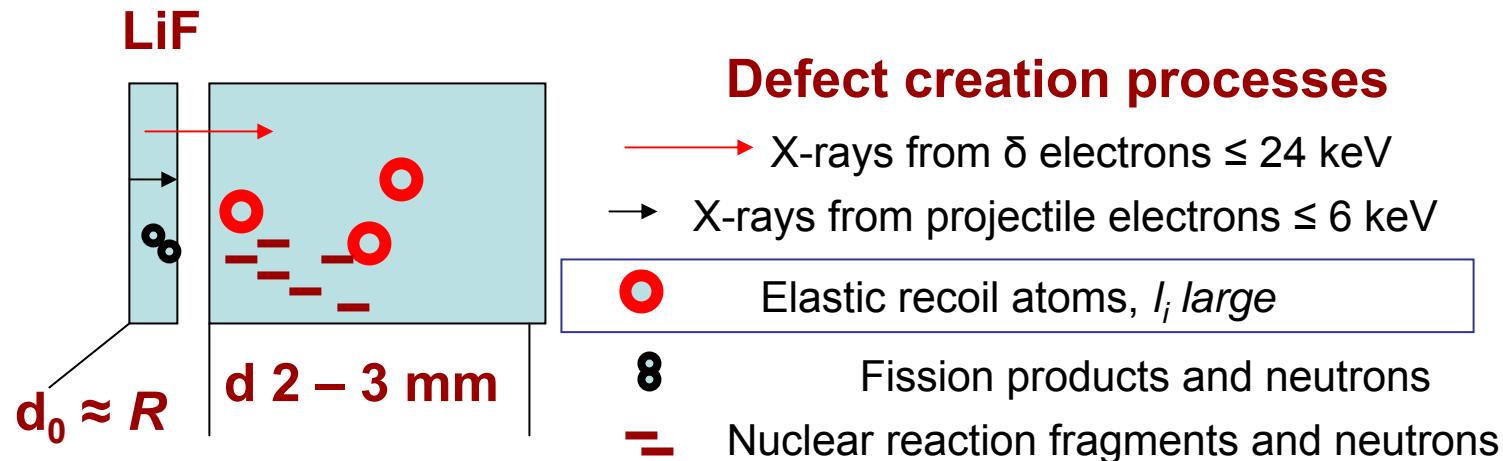
Similar results  
with Pb, Au, Xe,  
etc.

F centers can be  
detected at  
 $\Phi \geq 3 \times 10^{11} \text{ ions/cm}^2$



$$n_F = 1.8 \times 10^{15} \text{ cm}^{-2}; n_F(z > R)/n_F(z < R) \approx 10^{-3}$$

# Defects beyond the track $z > R$



Experiments with ions:

12-C 130 MeV  $R = 245 \mu m$   $2.5 \times 10^{13}$

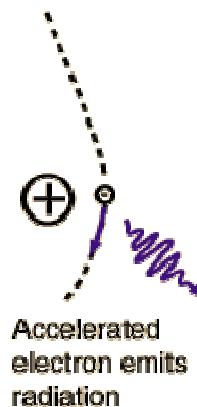
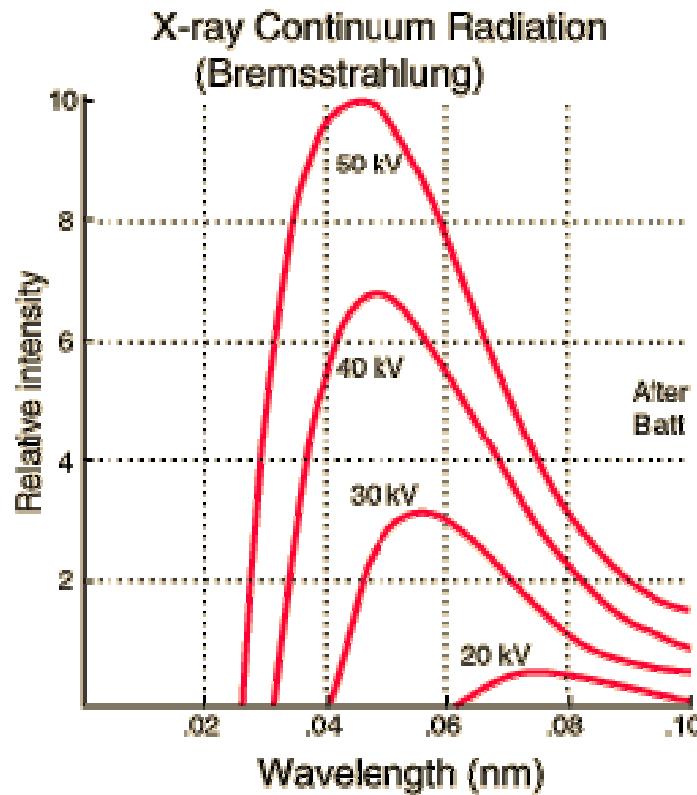
130-Xe 135 MeV  $R = 80 \mu m$   $5 \times 10^{12}$

197-Au 2100 MeV  $R = 95 \mu m$   $5 \times 10^{12}$

208-Pb 1600 MeV  $R = 69 \mu m$   $2 \times 10^{12}$

238-U 2500 MeV  $R = 89 \mu m$   $5 \times 10^{12}$

# Bremsstrahlung Spectrum



12 keV corresponds to 0.1 nm

# Conclusions

1. Alkali halides, especially LiF is an excellent model for damage studies under ion irradiation
2. New phenomena were observed in LiF under ion irradiation(dependences on  $dE/dx$ ,  $T_{irr}$ ,  $E_{ion}$ , etc.)
3. The color centers beyond the track can be produced by various processes: X-rays; recoil atoms; nuclear reaction fragments
4. Damage creation beyond the ion track, probably, takes place in any solid
5. Additional experiments are necessary to clear the mechanisms of defect creation beyond the track

# Colaboration

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E. Vasil`chenko

Ch. Lushchik

A. Lushchik

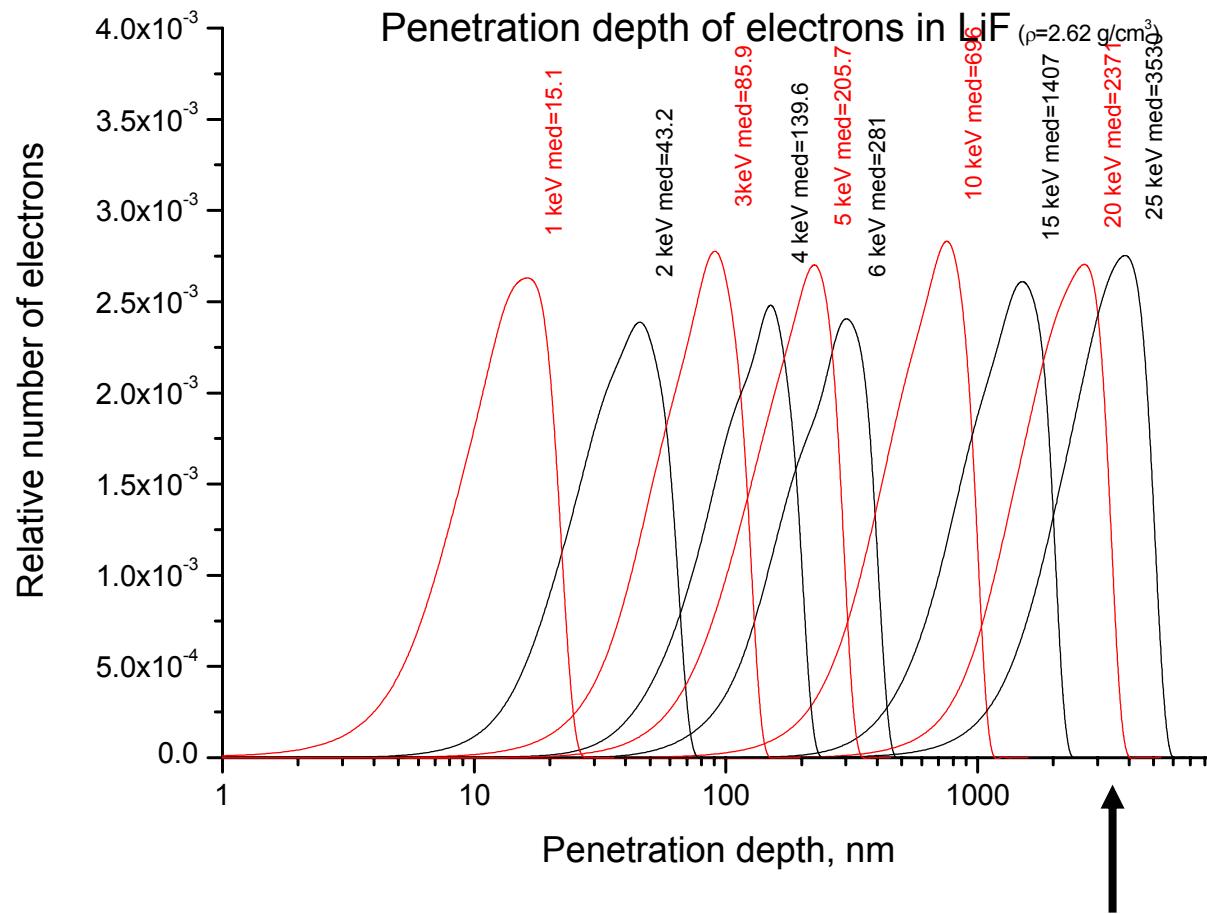
Kurchatov Institute, Moscow,  
Russia

A. V. Volkov

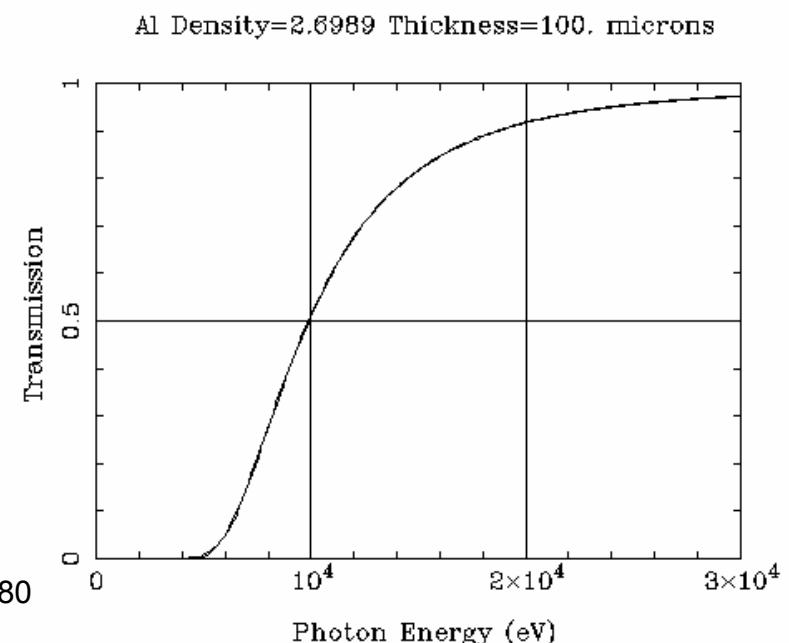
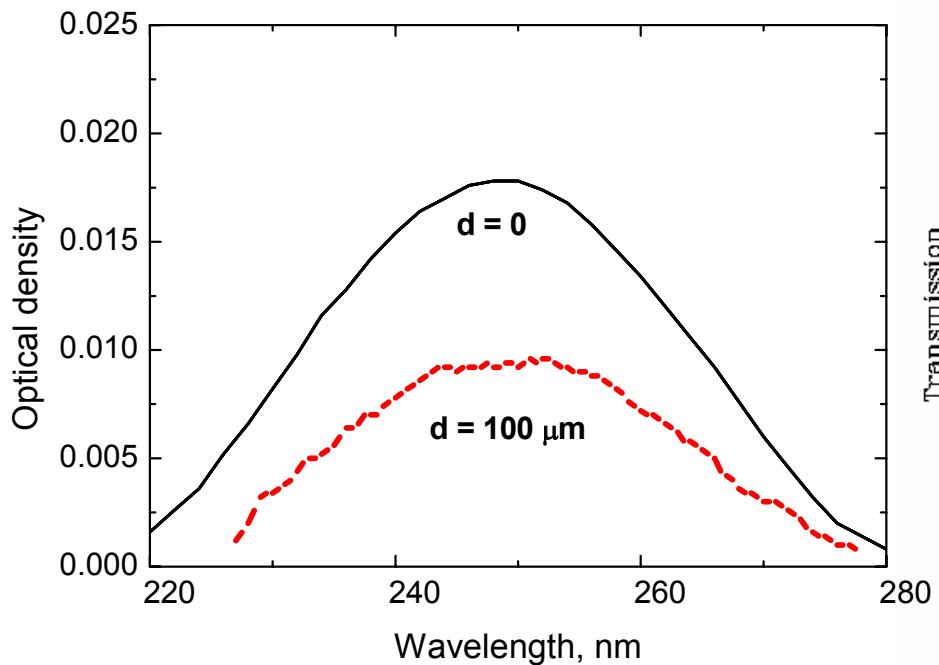
M. V. Sorokin

**Thank you for your  
attention**

# Penetration depth of $\delta$ electrons



# Transmission of the radiation



$$k_1 = 0.61 \pm 0.07 \quad k_2 = 0.50 \pm 0.07 ; \quad h\nu_x = 12 \pm 2 \text{ keV}$$

# F center concentration in the depth beyond the track: decreasing with the thickness

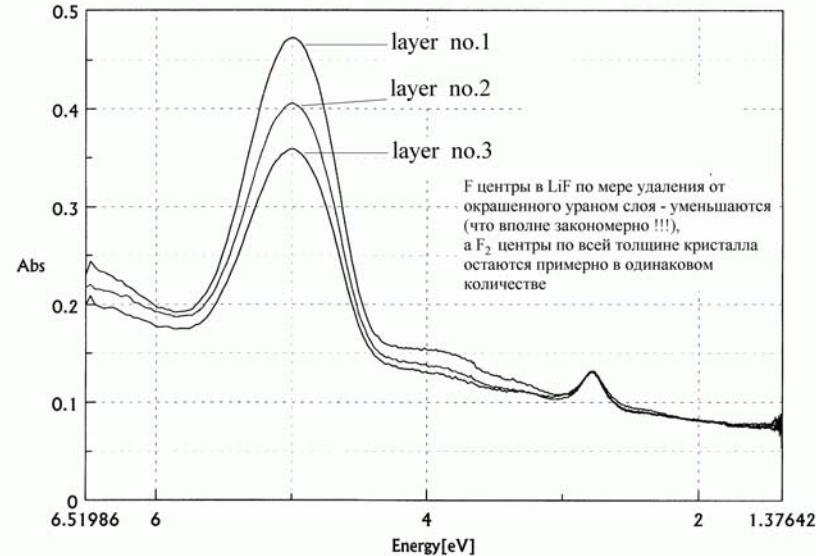
X-ray absorption

$$I = I_0 e^{-\mu d}$$

$$n_F(x) \sim \exp(-x/l)$$

Exponential decrease of the X – ray intensity

$$n_F \sim I_x$$



Date: 3/1/06 6:33PM  
File name: LiF\_238U\_11MeVn\_Flu\_e12\_d=2.92mm\_secpart\_up3-1\_eV.jws  
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Serial No.: C0295712  
Band width: 1.0 nm  
Response: Medium  
Measurement range: 1.37642 - 6.51986 eV  
Scanning speed: 100nm/min  
Sample ID: 824  
No. of cycle: 1

Sample name: EUGENY VASSILCHENKO  
Operator: Comment:

